

STQ1NE10L

General features

Туре	V _{DSS}	R _{DS(on)}	I _D
STQ1NE10L	100V	<0.4Ω	1A

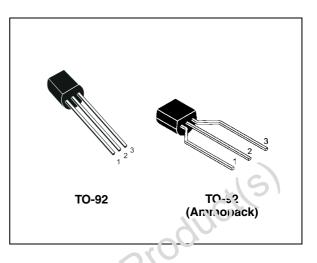
- Exceptional high dv/dt capability
- 100% avalanche tested
- Avalanche rugged technology
- Low threshold drive

Description

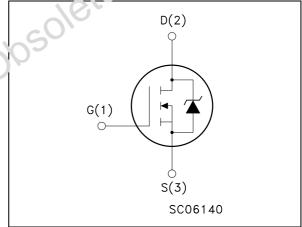
This Power MOSFET is the latest development of STMicroelectronics unique "Single Feature Size[™] strip-based process. The resulting transistor shows extremely high packing density for low on-resistance, rugged avalanche characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility.

;olete Productls **Applications**

Switching application



Internal schematic diagram



Order codes

Part number	Marking	Package	Packaging
STQ1NE10L	Q1NE10L	TO-92	Tube
STQ1NE10L-AP	Q1NE10L	TO-92	Ammopak

January 2	2007
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00501	Revision history



Table 1. Absolute maximum ratings

Electrical ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	100	V
V_{GS}	Gate-source voltage	± 16	V
I _D	Drain current (continuous) at $T_C = 25^{\circ}C$	1	Α
I _D	Drain current (continuous) at T _C =100°C	0.6	Α
I _{DG}	Drain gate current (continuous)	± 50	mA
I _{GS}	Gate source current (continuous)	± 50	mA
$I_{DM}^{(1)}$	Drain current (pulsed)	4	Α
$P_{TOT}^{(2)}$	Total dissipation at $T_{C} = 25^{\circ}C$	3	W
	Derating factor	0.025	W/°C
dv/dt ⁽³⁾	Peak diode recovery voltage slope	6	V/ns
$E_{AS}^{(4)}$	Single pulse avalanche energy	400	mJ
T _{stg}	Storage temperature		9
TJ	Operating junction temperature	-55 to 150	°C
2. Relate 3. I _{SD} ≤1/	vidth limited by safe operating area. d to Rthj -l A, di/dt $\leq 200A/\mu$ s, V _{DD} \leq V _{(BR)DSS} , T _J \leq T _{JMAX} g T _J = 25 °C, I _D = 1A, V _{DD} = 50V Thermal data	je je	
		Value	Lini

	Symbol	Parameter	Value	Unit
	R _{thJC}	Thermal resistance junction-case max	40	°C/W
	R _{thJA}	Thermal resistance junction-ambient max	125	°C/W
	TI	Maximum lead temperature for soldering purpose	260	°C
obsole	ter			



Electrical characteristics 2

 $(T_{CASE} = 25^{\circ}C \text{ unless otherwise specified})$

Table J.	On/on states					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DG}	Clamped voltage	$I_{D} = 250 \mu A, V_{GS} = 0$	100			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V_{DS} = Max rating V_{DS} = Max rating T_{C} = 125°C			1 10	μΑ μΑ
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ±16 V			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1		2.5	V
R _{DS(on)}	Static drain-source ON resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 0.5 \text{ A}$ $V_{GS} = 5 \text{ V}, \text{ I}_{D} = 0.5 \text{ A}$		0.30 0.35	0.40 0.45	Ω Ω
Table 4.	Dynamic	·		,01	6	

Table 3. On/off states

Table 4. Dynamic

Table 4.	Dynamic					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
9 _{fs}	Forward transconductance	$V_{DS} = 15 \text{ V}, \text{ I}_{D} = 0.5 \mu\text{A}$		2		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 25 V, f = 1MHz, V _{GS} = 0		345 45 20		pF pF pF
t _{r(on)} t _f	Turn-on time Rise time	$V_{DD} = 50 \text{ V}, \text{ I}_{D} = 0.5 \text{ A},$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V}$ <i>Figure 12</i>		11 12		ns ns ns
t _{d(off)} t _f	Turn-off delay time Fall time			20 13		ns ns
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 80 \text{ V}, \text{ I}_D = 1\text{ A},$ $V_{GS} = 5\text{ V}$ Figure 13		7 1.5 3.5		nC nC nC



Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
I _{SD}	Source-drain current				1	А
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)				4	Α
$V_{SD}^{(2)}$	Forward on voltage	I _{SD} =1A, V _{GS} =0			1.5	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 1A, di/dt = 100A/μs, V _{DD} =30V, Τ _J = 100°C		52 90 3.5		ns nC A

 Table 5.
 Source drain diode

1. Pulse width limited by safe operating area

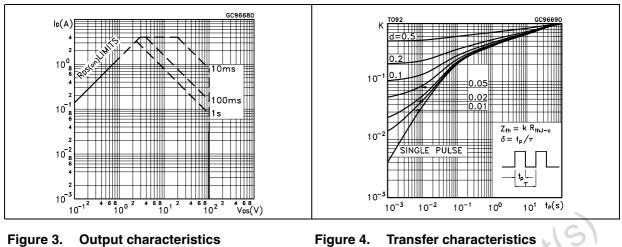
2. Pulsed: pulse duration=300µs, duly cycle 1.5%

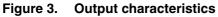


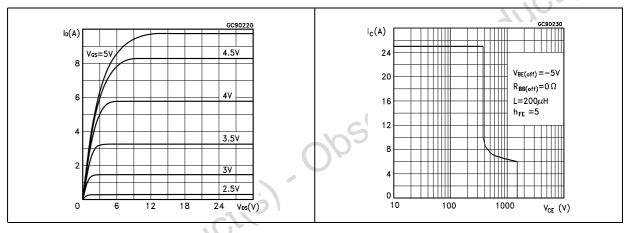
Electrical characteristics (curves) 2.1

Figure 1. Safe operating area

Figure 2. Thermal impedance







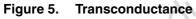
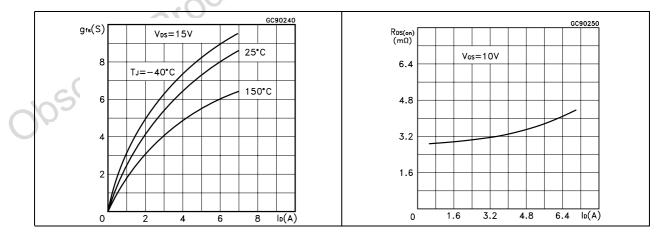
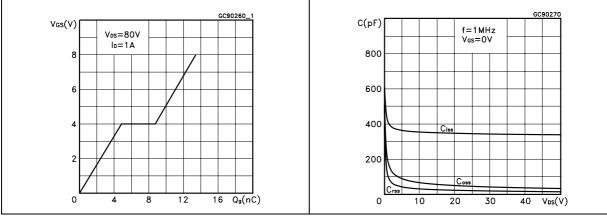


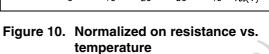
Figure 6. Static drain-source on resistance

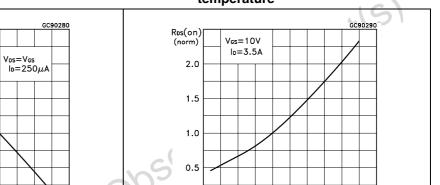




Gate charge vs. gate-source voltage Figure 8. Capacitance variations Figure 7.

Figure 9. Normalized gate threshold voltage vs. temperature





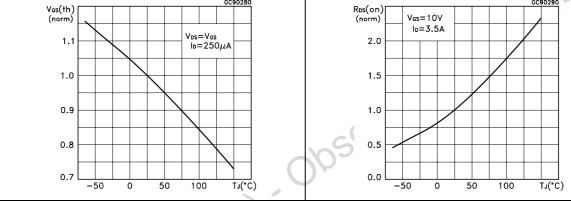
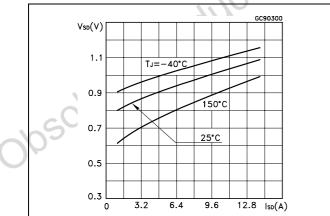


Figure 11. Source-drain diode forward characteristics



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Test circuit 3

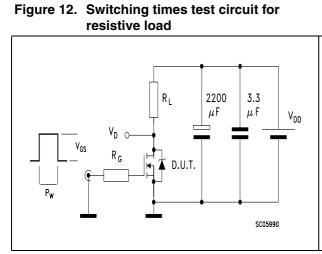


Figure 14. Test circuit for inductive load switching and diode recovery times

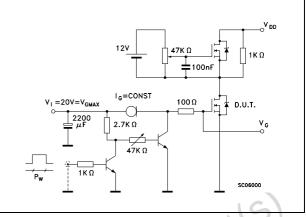
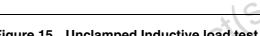
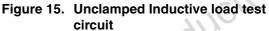
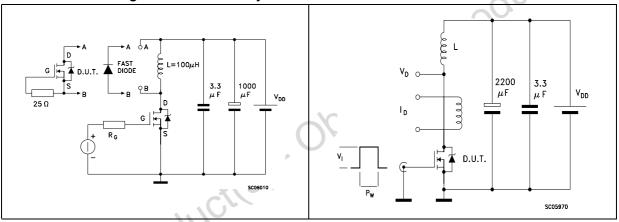
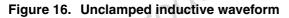


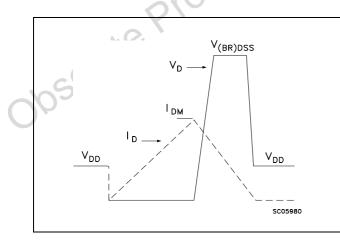
Figure 13. Gate charge test circuit











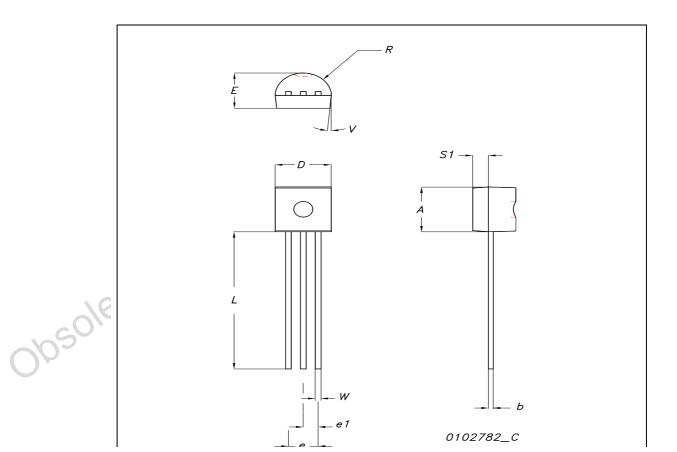
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

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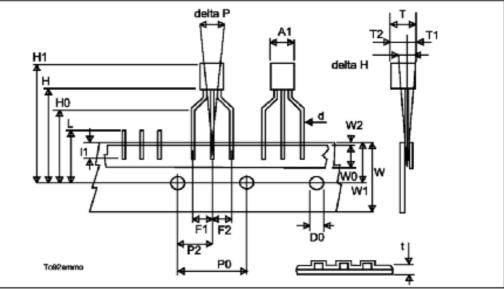
	TO-92 MECHANICAL DATA						
		mm.			inch		
DIM.	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX.	
А	4.32		4.95	0.170		0.194	
b	0.36		0.51	0.014		0.020	
D	4.45		4.95	0.175		0.194	
Е	3.30		3.94	0.130		0.155	
е	2.41		2.67	0.094		0.105	
e1	1.14		1.40	0.044		0.055	
L	12.70		15.49	0.50		0.610	
R	2.16		2.41	0.085		0.094	
S1	0.92		1.52	0.036		0.060	
W	0.41		0.56	0.016		0.022	
V		5°			5°		





DIM.		mm.			inch	
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A1			4.8			0.19
Т			3.8			0.15
T1			1.6			0.06
T2			2.3			0.09
d			0.48			0.02
P0	12.5	12.7	12.9	0.49	0.5	0.51
P2	5.65	6.35	7.05	0.22	0.25	0.27
F1, F2	2.44	2.54	2.94	0.09	0.1	0.11
delta H	-2		2	-0.08		0.08
w	17.5	18	19	0.69	0.71	0.74
W0	5.7	6	6.3	0.22	0.23	0.24
W1	8.5	9	9.25	0.33	0.35	0.36
W2			0.5			0.02
н	18.5		20.5	0.72		0.80
HO	15.5	16	16.5	0.61	0.63	0.65
H1			25			0.98
D0	3.8	4	4.2	0.15	0.157	0.16
t			0.9			0.035
L			11			0.43
11	3			0.11		





Obsole

5 Revision history

Date	Revision	Changes
21-Jun-2004	3	Complete version
31-Oct-2006	4	Document has been reformatted
31-Jan-2007	5	Typo mistake on Table 1.

obsolete Product(s). Obsolete Product(s)

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